

C-V measurements in AC-LGADs

Jennifer Ott

For the SCIPP team

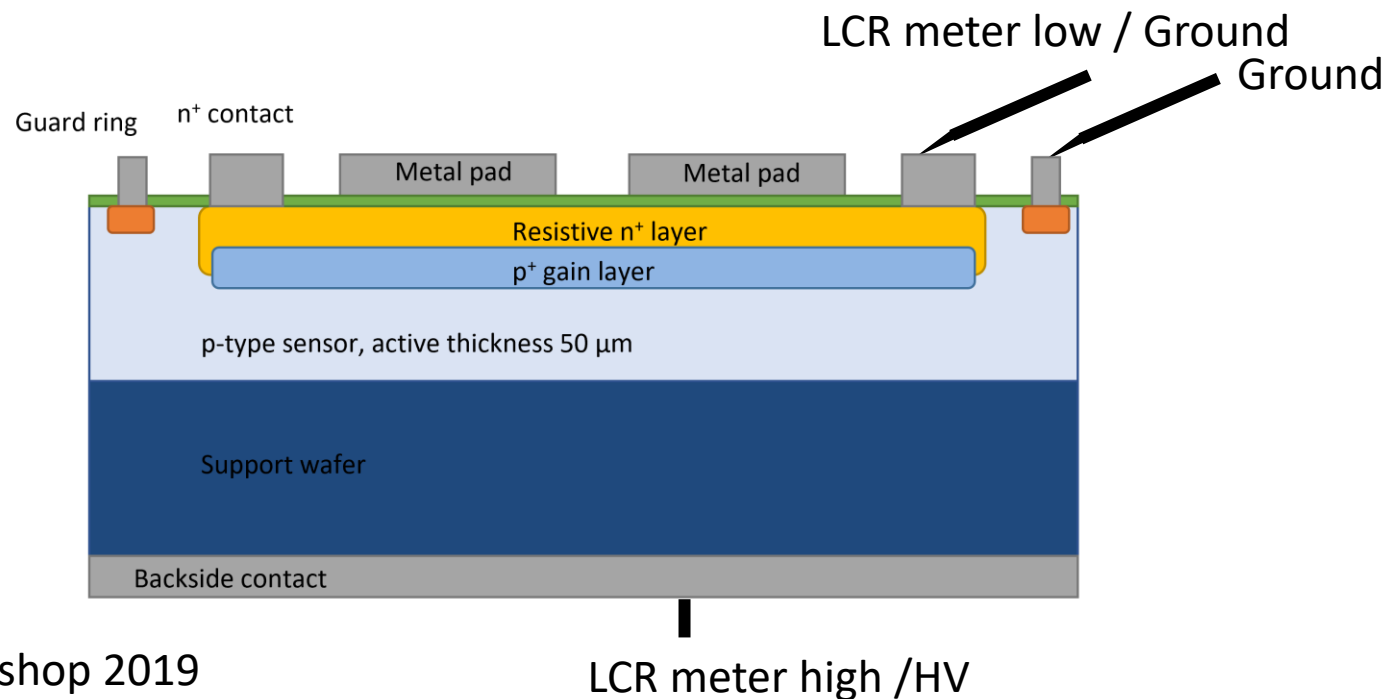
Sept 21, 2022

jeott@ucsc.edu

Standard C-V measurement

“Conventional” C-V measurement configuration: sensor backplane to front side electrode

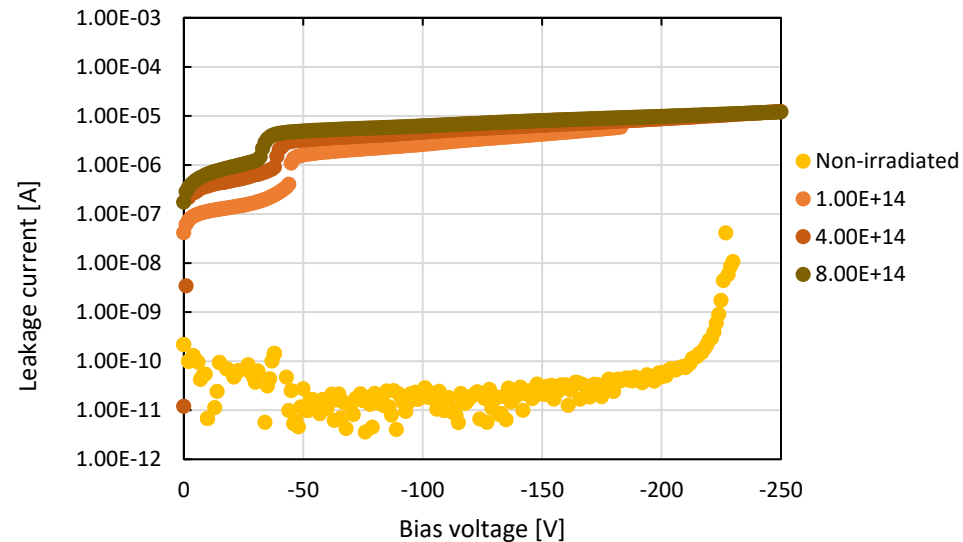
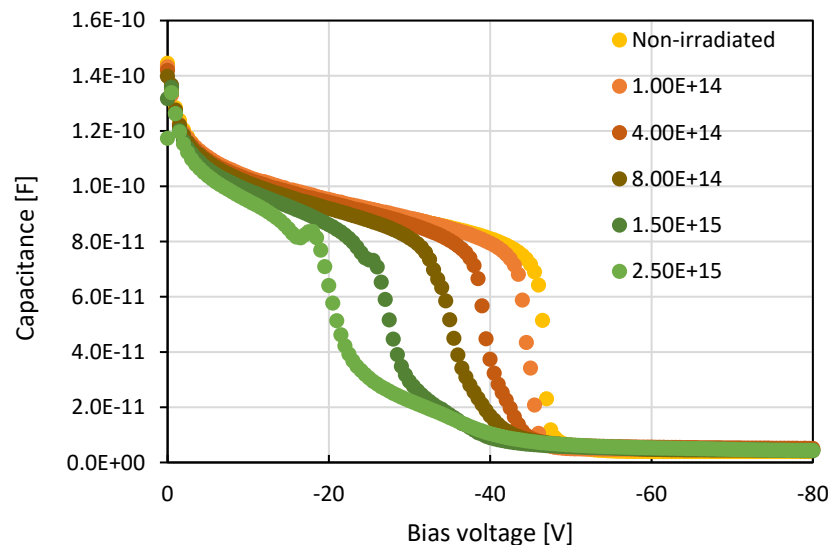
- In AC-LGADs, there is one shared n^+ layer with the DC contact – capacitance measured over the full sensor area
- Depending on area: **pF to 10s of pF**



Radiation damage

Irradiation has an impact on the bulk and on the gain layer, just like in other types of LGADs

- Bulk damage: increased leakage current and defect concentration – higher depletion voltage of the bulk volume
- Gain layer: “acceptor removal” – lower depletion voltage

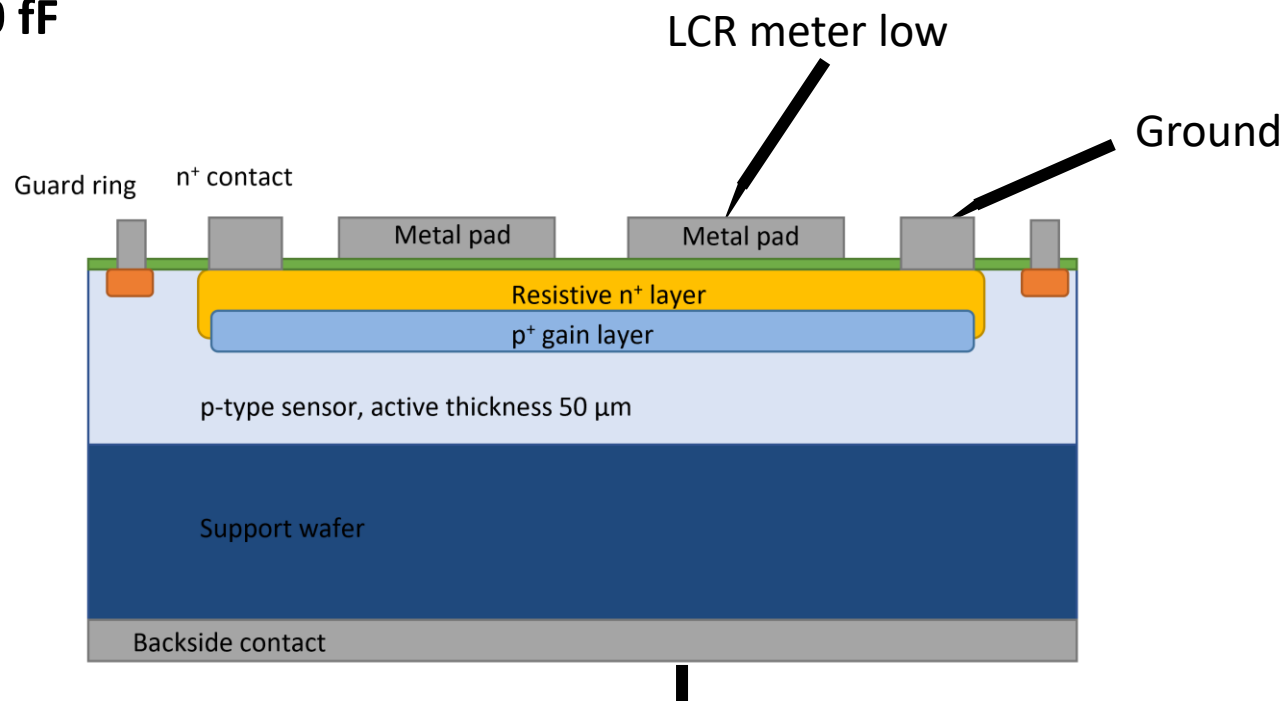
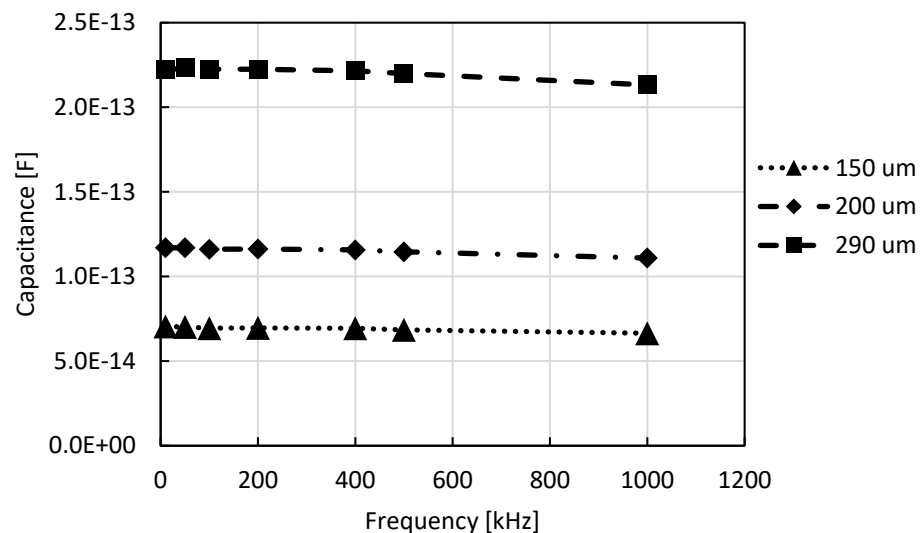


- Radiation levels of $\mathcal{O}(10^{14} \text{ cm}^{-2})$ as predicted for ePIC should not have a significant impact on sensor performance, but increase in leakage current needs to be considered

AC capacitance

Specific to AC-LGADs: measurement from backplane to individual AC metal pad

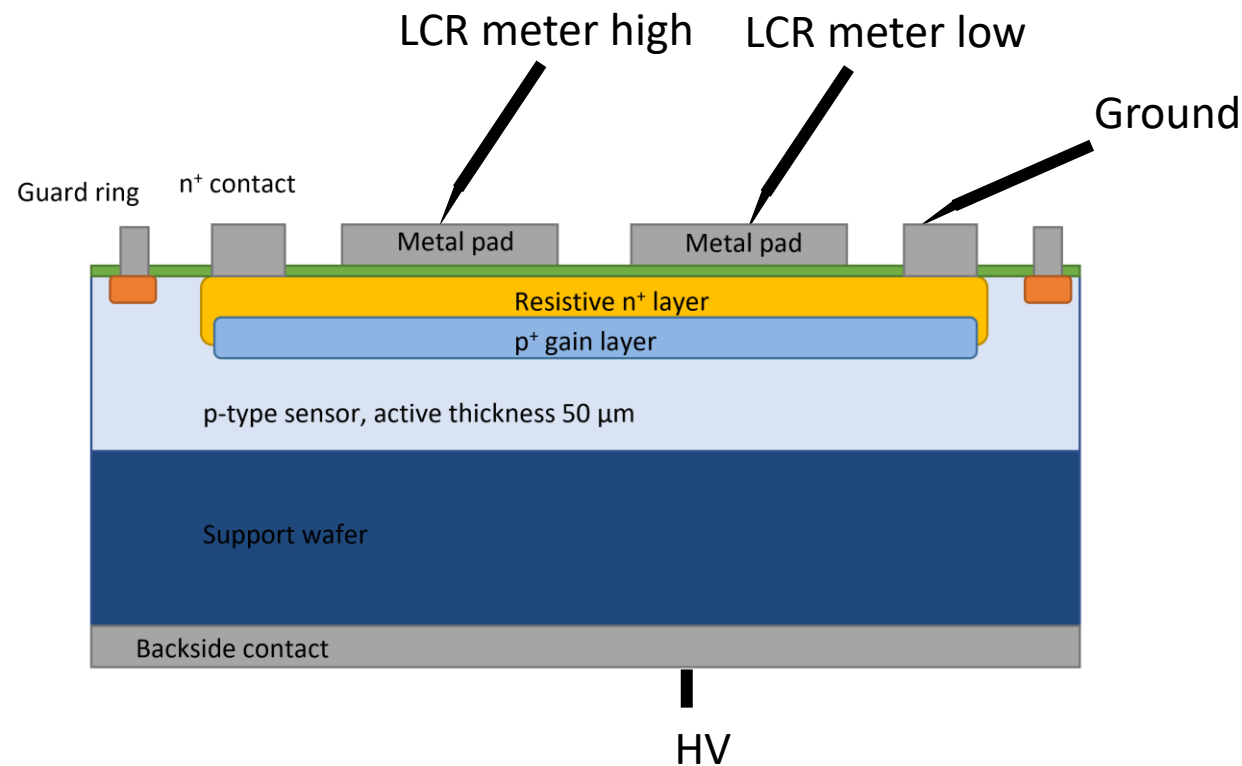
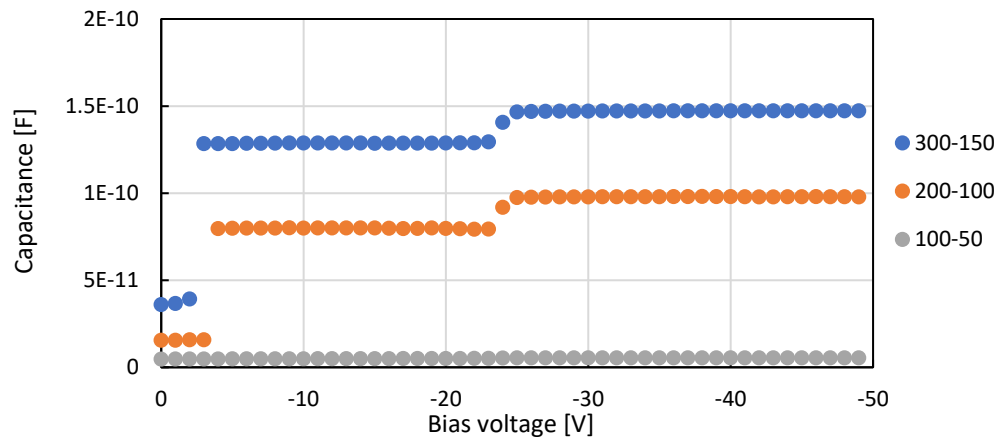
- Pad size affects the final capacitance values, since capacitance is directly proportional to the area
- Values after full depletion are relatively small compared to “regular” CV measurements: **for 150 μm pads, < 100 fF**



Interpad capacitance

Interpad capacitance: between two AC metal pads, sensor biasing from backplane as usual, grounding to the n+ DC contact

- Depletion visible, frequency dependence before depletion – capacitance component through the bulk
- A factor in the observed higher signal sharing for longer strips



cf. M. Tornago, 35th RD50 Workshop 2019

Reducing input capacitance by reducing metal?

E.g. cutting out the metal on strips, leaving a “frame” instead of a fully metallized strip, in FBK RSD2*

➤ Direct impact on electrode capacitance

